

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 295880US2PCT		SERIAL NO. 10/591,433	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Mikio IZUMI, et al.			
				FILING DATE September 1, 2006		GROUP 2108	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	WO 00/41101	07/13/2000	WIPO			
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	AW	Charles E. STROUD, et al., "Applying Built-In Self-Test to Majority Voting Fault Tolerant Circuits", VLSI Test Symposium, 1998. Proceedings. 16 th IEEE Monterey, CA, USA, April 26-30, 1998, Los Alamitos, CA, USA, IEEE COMPUT. SOC, US, April 26, 1998, pages 303-308, XP010277179					
	AX	R. E. BATTLE, et al., "Reactor Protection System Design Using Application-specific Integrated Circuits", 19000101, January 1, 1900, pages 389-396, XP009106740					
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	BA	B. S. KONG, et al., "CMOS differential logic family with self-timing and charge-recycling for high-speed and low-power VLSI", IEE Proceedings: Circuits Devices and System, Institution of Electrical Engineers, Stenvenage, GB, vol. 150, no. 1, February 6, 2003, pages 45-50, XP006019670				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner							
Date Considered							
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							